

# Size-effects in time-dependent mechanics in metallic MEMS

L.I.J.C. Bergers<sup>1,2,3,a</sup>, N.K.R. Delhey<sup>1</sup>, J.P.M. Hoefnagels<sup>1</sup>, and M.G.D. Geers<sup>1</sup>

<sup>1</sup> Eindhoven University of Technology, Dep. of Mechanical Engineering, P.O. Box 513, 5600 MB, Eindhoven, The Netherlands

<sup>2</sup> Foundation for Fundamental Research on Matter, P.O. Box 3021, 3502 GA, Utrecht, The Netherlands

<sup>3</sup> Materials Innovation Institute, P.O. Box 5008, 2600 GA, Delft, The Netherlands

## 1 Summary

Reliability of microelectromechanical systems (MEMS) depends a.o. on time-dependent deformation such as creep and fatigue [1]. It is known from literature that this behavior is affected by size-effects: the interaction between microstructural length scales and dimensional length scales [2,3]. Not much research has focused on characterizing size-effects in time-dependent material behavior, specifically for free-standing thin films [3]. This study investigates size-effects caused by grain statistics in time-dependent deformation in  $\mu\text{m}$ -sized free-standing aluminum cantilever beams.

A numeric-experimental method is used to determine material parameters. The experiment entails applying a constant deflection to the micro-beams for a prolonged period. The deflection is achieved with 50 nm resolution via a micro-clamp. The beams are then released. Immediately the deformation evolution is recorded by acquiring surface height profiles with a confocal optical profiler. Image correlation of the full-field beam profiles is applied to correct for specimen drift and tilt. The experiment yields the tip deflection as function of time with  $\sim 3$  nm precision. In the numerical part, this data is combined with a finite element model based on a standard-solid material model. In this way material parameters describing time-dependent behavior are extracted. The time constant for the deflection evolution is determined within 20%, as verified by *predicting* a different experiment. Figure 1 shows the model and the numeric prediction of an experiment.

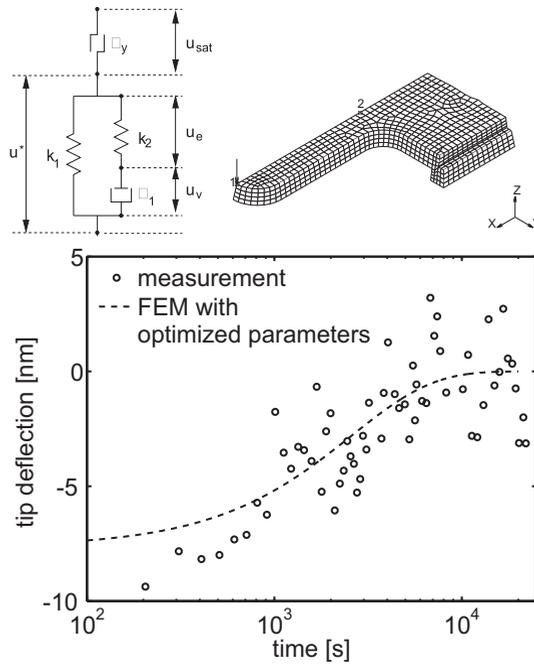
To investigate the size-effects of grain statistics, orientation imaging microscopy (OIM) is employed directly on the free-standing cantilevers, see figure 2. This work correlates the obtained time-dependent material parameters to the actual grain sizes, grain boundary length and texture orientation per specimen. Insights into the interplay between micro-mechanism and grain characteristic and the effect on the time-dependent material behavior are presented.

## References

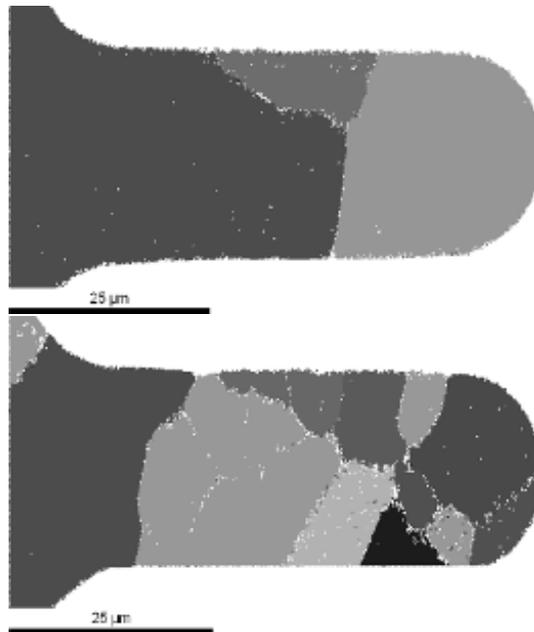
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<sup>a</sup> e-mail: l.i.j.c.bergers@tue.nl



**Fig. 1.** Numeric-experimental method to obtain material parameters from a time-dependent behavior measurement.



**Fig. 2.** Grains in cantilever beams visualized by OIM for a specimen containing (a) few grains and (b) many grains.